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# **PFM S/LW BDA Compliance Matrix**

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# **1** Introduction

This document summarises the compliance of the SPIRE PFM S/LW BDA (as delivered) with the requirements as laid out in the Detector Subsystem Specification Document (BDA SSSD: SPIRE-PRJ-000456, Issue 3.2, Jan. 7 2003). It reproduces the relavant tables and notes from the SSSD with additional columns indicating compliance. Compliance may be by design (as documented in the DBA design documentation, by test (as reported in the EIDP) or by analysis (reported as indicated in the table). Requirements that require uinstrument-level verification are deemed non-applicable (N/A) for acceptance of the unit as delivered.

# 2 Compliance with specifications

# 2.1 Performance Specification

Specification	Description	Requirement	Minimum	Design	PFM S/LW BDA
ID		Reference	Performance	Value	Compliance
BDA-PER-01	Maximum number of bad detectors in each BDA	IRD-DETP-R04 IRD-DETS-R04	11 (P/LW) 22 (P/MW) 35 (P/SW) 5 (S/LW) 9 (S/SW)	4 (P/LW) 9 (P/MW) 14 (P/SW) 2 (S/LW) 4 (S/SW)	Compliant by test No. of bad pixels as defined below is 2.
BDA-PER-02	The ratio of photon NEP due to radiation absorbed by the detector and total NEP, given as $(NEPphoton/NEPtot)^2$ NEP includes all sources of noise at 1 Hz, measured at 300 mK, assuming a total readout noise of 10 $nV/\sqrt{Hz}$ and the values in Table 3-1-2.	IRD-DETP-R01 HR-SP-JPL- RFW-002	0.46 (P/LW) 0.53 (P/MW) 0.59 (P/SW) 0.50 (S/LW) 0.59 (S/SW)	0.55 (P/LW) 0.63 (P/MW) 0.70 (P/SW) 0.60 (S/LW) 0.71 (S/SW)	Compliant by test All functional pixels have DQE ≥ 0.5 Median value is 0.53 Note RFW-02 submitted to reduce spec by 6-9 % due to lower than expected R0 value. Without this waiver, future arrays may not meet yield requirement based on DQE. Operational risk of changing NTD Ge material was judged to be unacceptable.
BDA-PER-03	The optical efficiency of the BDA horn and bolometer assembly for the photometer arrays over the optical passband. at the centre of the bandpass assuming ? <sup>2</sup> throughput and a beam filling source	IRD-DETP-R01	0.65	0.85	N/A
BDA-PER-04	The optical efficiency of the short wavelength spectrometer horn arrays and bolometer assembly at 250 µm	IRD-DETS-R01 IRD-DETS-R08	-	0.7	N/A



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BDA-PER-05	assuming 2? <sup>2</sup> throughput and a beam filling source and measured using an optical filter with a width of 15% of the central wavelength The optical efficiency of the long wavelength spectrometer horn arrays and bolometer assembly at 350 µm assuming 3? <sup>2</sup> throughput and a beam filling source and	IRD-DETS-R01 IRD-DETS-R08	-	0.75	Compliant by test. All functional pixels have optical efficiency ≥ 0.72. Median value is 0.75
	measured using an optical filter with a width of 15% of the central wavelength				
BDA-PER-06	The photometer detector time constant (based on a maximum modulation frequency of 2 Hz)	IRD-DETP-R02	32 ms	18 ms (P/LW) 13 ms (P/MW) 11 ms (P/SW)	N/A
BDA-PER-07	The spectrometer detector time constant (based on a maximum signal frequency of 20 Hz).	IRD-DETS-R02	14 ms (S/LW) 8 ms (S/SW)	4.2 ms (S/LW) 4.2 ms (S/SW)	Compliant by test. All functional pixels have time constant = 8.25 ms. Median value is
					5.1 ms
BDA-PER-08	The uniformity of the calibrated responsivity.	IRD-DETP-R03 IRD-DETS-R03	0.99	0.99	Not characterised – to be verified at system level
BDA-PER-09	Detector cross-talk.	IRD-DETP-R05 IRD-DETP-R06 IRD-DETS-R05 IRD-DETS-R06	< 5 % nearest neighbors	1 % nearest neighbors 0.1% non- nearest neighbors	Not characterised – to be verified at system level
BDA-PER-10	The 1/f knee frequency (frequency at which total noise is $\sqrt{2}$ larger than white level).		0.1 Hz	0.03 Hz	Compliant by test. < 30 mHz for all functional pixels
BDA-PER-11	The detectors shall be designed for optimal performance under the following levels of absorbed power (pW).	JPL		2.5 (P/LW) 3.3 (P/MW) 4.1 (P/SW) 10.6 (S/LW) 10.8 (S/SW)	Compliant by design
BDA-PER-12	The detectors and readout electronics shall be designed to function under a radiation background a factor of two lower or a factor of 5 higher than the nominal values assumed in BDA-PER- 11				BDAs compliant by analysis carried out by Matt Griffin and presented at SPIRE IBDR, March 2002. Max bolometer voltage = 10 mVrms, compliant with DRCU max = 17



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				mVrms. Note thermistors saturate at 31 and 69 mVrms bias.
BDA-PER-13	The positional repeatability of the focal plane structure shall be $< 125 \mu$ m orthogonal to the optical axis, and $< 500 \mu$ m along the optical axis. The rotational repeatability around the optical axis shall be $< 0.5$ deg.	RAL	<125 µm orthogonal <500 µm along axis <0.5 degree rotation	Compliant by test

Notes:

BDA-PER-01: A "bad detector" is here defined as one that does not achieve, at the BDA output, performance compatible with the minimum performance values for BDA-PER-2 to 10.

BDA-PER-02: The bolometer performance estimation assumes the following nominal photon NEPs (W/ $\sqrt{Hz}$ ) referred to power absorbed at the detector:

P/LW:	4.6 x 10 <sup>-17</sup>
P/MW:	$6.3 \ge 10^{-17}$
P/SW:	8.2 x 10 <sup>-17</sup>
S/LW:	10.5 x 10 <sup>-17</sup>
S/SW:	13.6 x 10 <sup>-17</sup>

BDA-PER-02 and BDA-PER-11: The optical loading and photon NEP assume the following nominal optical efficiencies of the bolometer and feedhorn combinations:

P/LW	0.65
P/MW	0.65
P/SW	0.65
S/LW	0.65
S/SW	0.70

BDA-PER-11: The values of optical loading are based on the SPIRE instrument sensitivity models, and incorporate the following assumptions:

(i) the thermal background from the telescope corresponds to a temperature of 80 K and an emissivity of 4%;

(ii) the total power loading on the detectors is dominated by the telescope, with a negligible contribution from the instrument itself;

(iii) the spectral passbands are defined by a combination of BDA waveguide cut-off and submillimetre filters resulting in a negligible contribution to the background and the NEP from out-of band radiation.

#### 2.2 Functional Specification

Specification ID	Description	Requirement Reference	PFM SLW BDA Compliance
BDA-FUN-01	The photometer angular response shall be defined by a	IRD-DETP-R07	Compliant by



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	straight-walled conical feedhorn.		design
BDA-FUN-02	The spectrometer angular response shall be defined by a	IRD-DETS-R07	Compliant by
	multi-mode feedhorn.		design
BDA-FUN-03	The spectral long-wavelength cutoff determined by the	IRD-DETP-R08	Compliant by
	feedhorn output waveguide aperture will be 670 µm.	IRD-DETS-R08	design

# 2.3 Technical Specification

Note: For all budgetary resource values (mass; thermal dissipation; temperature) the instrument will hold a margin against the design value – 20% unless indicated otherwise. Where the minimum performance value is below the margin (BDA-TEC-06, JFET-TEC-05), a system level analysis will be conducted to investigate the effect of increasing the resource allocations to the minimum performance values indicated here. A future release of this document will reflect updated resource allocations and minimum performance levels.

Specification	Description	Requirement	PFM SLW BDA
ID		Reference	Compliance
BDA-TEC-01	The BDA shall accommodate a defined mechanical	IRD-DETS-R08	Compliant by design
	interface to the 2 K structure.	IRD-DETP-R14	
		IRD-STRP-R01	
BDA-TEC-02	The BDA shall provide an attachment point and/or	IRD-STRP-R01	Compliant by design
	a thermal interconnect to a 300 mK thermal strap.		
BDA-TEC-03	The BDA mass will have a design value of 600 gm	IRD-SUBS-03	Compliant by design
	connectors.		
BDA-TEC-04	The first resonant frequency of the BDA will be >	IRD-DETP-R15	Compliant by qual unit
	200  Hz, with a goal of > $250  Hz$ .	IRD-DETS-R16	test
BDA-TEC-05	The mechanical envelope of the BDA will be	IRD-DETP-R12	Compliant by design
	described by the Detector Subsystem Interface	IRD-DETS-R13	
	Control Document [RD5].		
BDA-TEC-06	The total power load on the 300 mK cooler from	IRD-DETP-R13	Compliant by design.
	the BDAs will be $< 15 \mu\text{W}$ (minimum		Note measured heat
	performance); $< 8 \mu W$ (design value). This		load of $< 2.9$ uW is an
	assumes the focal plane mount is held at 1.7 K.		upper limit, intended to
			verify the unit does not
			have a cold touch.
			Dominant error is
			calibration of the fridge
			load at low applied
			fridge time constant
DDA TEC 07	The new of allocated for temperature control of the		N/A
DDA-TEC-0/	The power anocated for temperature control of the $^{3}$ Le stage is 2 uNV		IN/A
	He stage is 2 μW.		

#### 2.4 Operational Specification

Specification	Description	Requirement	PFM SLW BDA
ID		Reference	Compliance
BDA-SAF-01	Failure of a BDA or JFET module, or one of its	IRD-SAFE-R07	Compliant by
	components, as tabulated in BDA-SAF-03 to 06, shall		design
	not affect the health of any other subsystem, the		
	instrument, or the interface with the satellite.		
BDA-SAF-02	Any on-ground failure of a component of a BDA or	IRD-SAFE-R08	N/A
	JFET module will result in the entire module being		



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	removed and either replaced or refurbished at JPL at module level.		
BDA-SAF-03	Separate sets of 2 x 3 overlapping photometer pixels that are to be used for chopped point source observations shall not be served by the same 24-channel JFET membrane.		N/A
	The particular pixel set to be designated as the redundant set will be specified by the SPIRE Project.		
BDA-SAF-04	Any in-flight failure of any component of a BDA or JFET module shall not damage any redundant or backup component designed to replace that component. The only redundant hardware related to the BDA are bias and power wiring, RF filter modules, and back-up modules for the warm electronics.		Compliant by design of harness and electronics
BDA-SAF-05	The power supplies to each individual JFET 24-channel membrane shall be commandable ON/OFF (see BDA- DRCU-06)	IRD-SAFE-R07	N/A

## 2.5 Reliability

Specification ID	Description	Requirement Reference	PFM SLW BDA Compliance
BDA-REL-01	Failure of a BDA and a JFET module shall not lead to the total loss of instrument operations, as tabulated in BDA-SAF-03 to 04.	IRD-REL-R01	Compliant by design
BDA-REL-02	Observations can continue in degraded mode in the event of failure of the cold beam steering mirror.	IRD-REL-R02	Compliant by design
BDA-REL-03	Point source observations can continue in degraded mode in the event of misalignment of the photometer or spectrometer BDAs.	IRD-REL-R02	Compliant by design
BDA-REL-04	Single-point failures in the detector and JFET wiring (detector bias, JFET power) are to be duplicated. The RF filter modules on these lines will also be redundant.	IRD-REL-R03	Compliant by design
BDA-REL-05	BDA temperature stabilisation shall be implemented by an interruptible software-driven control loop.	IRD-REL-R04 IRD-REL-R05	Compliant by design

# 2.6 Interface Requirements

Requirement	Description	Reference	PFM SLW BDA
ID			Compliance
BDA-HCO-01	Design values of detector performance requires a	IRD-COOL-R01	Compliant by
	temperature < 290 mK at the point of contact to the	BDA-PER-02	design. To be
	BDA. Design value sensitivities assume 300 mK at		confirmed by
	the detector.		instrument-level
			testing of the CQM.
BDA-HCO-02	Design values of detector performance require	IRD-COOL-R05	N/A
	temperature stability at the point of thermal control	BDA-PER-10	Compliance to be
	(near the evaporator) of 10 $\mu$ K/ $\sqrt{Hz}$ from 0.1 – 10		verified by
	Hz. This assumes that the BDA acts as a 100-s		instrument-level
	thermal low-pass filter.		testing of the CQM.
BDA-HCO-03	Maximum allowed thermal drift at the point of	IRD-COOL-R04	N/A
	thermal control (near the evaporator) is 1 mK/hr. This	BDA-PER-10	Compliance to be
	assumes that the BDA acts as a 100 s thermal low-	BDA-HCO-02	verified by
	pass filter.		instrument-level
			testing of the CQM.



#### 2.6.1 Design and Manufacture Specification

Specification ID	Description	Requirement Reference	PFM SLW BDA Compliance
	BDA design		<b>_</b>
BDA-DES-01	The P/SW array is to have 139 detectors operating over a band centred on 250 $\mu$ m with $\lambda/\Delta\lambda = 3$ , in a close-packed array of 2F $\lambda$ feedhorns.	IRD-PHOT-R02 IRD-DETP-R07	N/A
BDA-DES-02	The P/MW array is to have 88 detectors operating over a band centred on 350 $\mu$ m with $\lambda/\Delta\lambda = 3$ , in a close-packed array of 2F $\lambda$ feedhorns.	IRD-PHOT-R02 IRD-DETP-R07	N/A
BDA-DES-03	The P/LW array is to have 43 detectors operating over a band centred on 500 $\mu$ m with $\lambda/\Delta\lambda = 3$ , in a close-packed array of 2F $\lambda$ feedhorns.	IRD-PHOT-R02 IRD-DETP-R07	N/A
BDA-DES-04	The S/SW array is to have 37 detectors for FTS spectroscopy between 200 and 325 $\mu$ m in a close-packed array of feedhorns with dimensions as given in Table 3-4-1.	IRD-SPEC-R04 IRD-DETS-R07	N/A
BDA-DES-05	The S/LW array is to have 19 detectors for FTS spectroscopy between $315 \mu\text{m}$ and $670 \mu\text{m}$ in a close-packed array of feedhorns with dimensions as given in Table 3-4-1.	IRD-SPEC-R04 IRD-DETS-R07	Compliant by design
BDA-DES-06	For all sets of detectors which are designed to overlap on the sky, the internal relative alignment of the corresponding feedhorn centres in the three photometer arrays or two spectrometer arrays shall be $\pm 40 \mu\text{m}$ (corresponding to a co-alignment accuracy of $\pm 0.5$ " on the sky). "Internal relative alignment" here is defined as the alignment of the detectors wrt each other when the respective BDAs are optimally co-aligned at their mechanical interfaces in a manner consistent with BDA- STR-01.	RAL	The S/SW and S/LW arrays meet 40 µm requirement. Compliance of co-alignment is to be established at system level.
BDA-DES-07	The BDA will accommodate cryogenic load resistors for current bias.	JPL	Compliant by design
BDA-DES-08	The BDA will provide electrical connector ports for ease of integration into the instrument.	JPL	Compliant by design
BDA-DES-09	The BDA will incorporate a differential readout scheme and harness design to minimize EMI/EMC and microphonic susceptibility.	JPL	Compliant by design
BDA-DES-10	The BDA assemblies shall be sine vibration tested at a temperature T < 90 K under the following qualification levels: a vibration input level at the base of 60 g between 5-100 Hz, or 11-mm amplitude at the base, whichever is less severe, at a sweep rate of 2 oct/min. Acceptance sweep rate is 4 oct/min. and acceptance amplitude is lower by 1.5. The BDA assemblies shall be random vibration tested at a temperature T < 90 K under the following qualification levels:	AD2	Compliant by test on qual. unit



	The input spectrum for the BDA in any direction is: * 0.8 g <sup>2</sup> /Hz between 100 and 300 Hz * Ramp-up between 20 and 100 Hz at +6 dB/oct * Ramp-down between 300 and 2000 Hz at -6 dB/oct		
	The input to the BDA is allowed to be notched at resonance to a level equal in g rms to 100 g for the suspended mass, taking into account a 4-sigma variation of the measured rms signal, in order not to exceed a quasi- static equivalent loading of the BDA of 100 g. The notch width at full depth should not exceed 1/3 octave band- width, with a ramp-up and ramp down of 10 db per octave.		
	If JPL experience major problems in maintaining the 100- g limit while keeping within the notching scheme as defined above, then the spectrum shall be revised by mutual agreement between JPL and the Project Team.		
	Notes: 1. It is possible, but not certain, that the above levels may be relaxed in the future taking into account the responses of individual BDAs.		
	2. Acceptance levels are a factor of 2.25 ( $g^2/Hz$ ) or 1.5 (g- rms) lower than qualification levels. Accordingly, for acceptance tests, the notched random vibration spectrum shall be such as not to exceed a quasi-static load of 100/(1.5) = 67 g.		
	3. Duration of tests: 120 seconds per axis qualification; 60 seconds per axis acceptance.		
BDA-DES-11	The BDA and JFET assemblies shall not exceed a temperature of 80 C and duration longer than a combined 300 total hours during bakeout testing at component, instrument and spacecraft level. Note that a change in the maximum temperature in this requirement would result in a change in the duration.	JPL	N/A

# 2.7 Feedhorn and Array Backshort Parameters

The tables below summarise the detailed specifications for the feedhorns and the detector backshort distances.

$\lambda_{\rm o}$	=	Nominal band centre wavelength
$\lambda_{b}$	=	Wavelength for which bolometer backshort distance is optimised
$\lambda_{\mathrm{U}}$	=	Nominal long-wavelength edge (defined by the waveguide diameter)
$\lambda_{\rm L}$	=	Nominal short-wavelength edge (defined by edge filter in front of horn)
$\lambda_o/\Delta\lambda$	=	Bandwidth assuming that an edge filter at exactly $\lambda_L$ is in front of the horn
Defocus	=	Required position of focus with respect to the horn aperture. Note: this places a requirement on the position of the horn wrt the mechanical interface of the BDA, which is to be specified in the Interface Control Document, consistent with this table.

Tolerances quoted correspond to maximum and minimum values acceptable for any horn (not the rms of a set of horns).



# **Herschel SPIRE**

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Feedhorn and filter specifications for the spectrometer								
<b>FTS Bands</b>		Array						
	S/SW (N/A)		S/LW			Status with respect to specification		
Number of horns		37			19			Redundant with BDA-DES-04
l <sub>o</sub>	m	258			487			N/A
l <sub>b</sub>	m	275			450			N/A
<b>l</b> <sub>L</sub> (50% points)	m	190	+/-	2	300	+/-	3	N/A: Reported in Cardiff University Filters EIDP
$\mathbf{l}_{\mathrm{L}}$ (90% trans. points)	m	200	+/-	2	315	+/-	3	N/A: Reported in Cardiff University Filters EIDP
l <sub>U</sub>	m	321	to	329	666	to	683	Not measured
<b>1/D1</b> (50% points)		1.83	to	1.99	1.27	to	1.34	N/A (redundant with $\lambda_U$ and $\lambda_L$ .)
Horn length	m	23680	+/-	200	4636 <mark>0</mark>	+/-	200	In spec. by design. Not measured directly.
Horn centre-centre distance	m	2250	+/-	20	3900	+/-	20	In spec. by design. Not measured directly. Waveguide centre-centre distances are all in spec. except for two slightly out.
Horn internal aperture	m	2150	+/-	5	3800	+/-	9	In spec. by test for all horns.
Waveguide length	m	550	to	600	900	to	950	In spec. by design. Not measured.
Waveguide diameter	m	188	to	193	390	to	400	In spec. by test for all waveguides.
Defocus	m	0	+/-	500	0	+/-	500	N/A
Backshort length	m	69	+/-	7	113	+/-	11	Out of spec. Average = 97.1 μm; max. = 106.5 μm; min. = 91.5 μm Two of the 19 array pixels are within spec. Consequences are acceptable because the primary requirement on optical efficiency (BDA-PER-05) is met.

#### 2.8 Verification Requirements

Verification ID	Description	Reference
BDA-VER-01	To carry out the tests on the BDA QM listed in SSSD Table 2-7-1.	IRD-VER-R01
		IRD-VER-R03
BDA-VER-02	To carry out the tests on the BDA PFM listed in SSSD Table 2-7-1.	IRD-VER-R01
		IRD-VER-R04
BDA-VER-03	To carry out the tests on the BDA FS listed in SSSE Table 23-7-1.	IRD-VER-R01
		IRD-VER-R04



SSSD Table 3.7.1						
Test	CQM	PFM	FS	PFM SLW BDA Compliance		
Vibration:	Q	Α	Α	Waivers agreed by SPIRE Project on:		
				(i) sine vibration as per HR-SP-JPL-RFW-		
				005;		
				(ii) only one minute random vibration duration		
				as per test report W/O101369 in EIDP.		
Thermal cycle:	D/Q	Α	Α	Compliant		
Vacuum cycle	D/Q	Α	Α	Compliant		
Lifetime:	D	-	-	N/A		
Soak/cycle:	D	-	-	N/A		
Radiation tolerance:	D	-	-	N/A		
Thermal range:	D	-	-	N/A		
Thermal stability (Instrument Level):	Q	Α	Α	N/A		
Microphonics (Instrument Level):	Q	Α	Α	N/A		
Ionising radiation:	D	-	-	N/A		
EMI (Instrument Level):	Q	Α	Α	N/A		
EMC (Satellite Level):	Q	Α	Α	N/A		

**Table 23-7-1:** Test matrix for the BDA and JFET modules. Q indicates a test carried out at qualification level for qualification times; A indicates a test carried out at acceptance level; D indicates a qualification test carried out by design, including unit-level testing and engineering analysis. An X indicates that this test is carried out and is a characterisation type test or the level is irrelevant. A dash indicates that no test will be done on this model/unit.